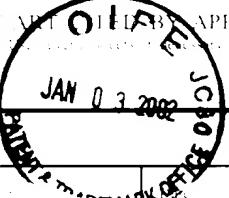


FEB 11 2002		U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		EXAMINER: J. REED		SERIAL NO.: 09/532,622	
LIST OF APPS FILED BY APPLICANT				SEARCHED		INDEXED	
JAN 8 0 2002				JAN 14 2002		JAN 14 2002	
SEARCHED STATEMENTS							
Examiner Initials		Document Number	Date	Searcher	Class	Subclass	Patent Number
EF	AA	09/532,622		Reed, J.			02/02/02
ET	AB	09/532,622		Reed, J.			02/02/02
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Patent Number	
AL						Yes	No
AM							
AN							
AO							
AP							
OTHER REFERENCES (excluding Authors, Title, Date, Patent, Pages, Etc.)							
	AA						
	AB						
	AC						
	AD						
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	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
RECEIVED JAN 14 2002 TC 1700							
EXAMINER <i>C. Reed</i>	DATE CONSIDERED 5/13/02						
EXAMINER: Initials reference considered whether application is in conformance with MPEP 601.05 and if application is in conformance and if the application is in accordance with the requirements of 37 CFR 1.56							

U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. MEE 1087	SERIAL NO. 6,488,821		
LIST OF ALL OTHER APPLICANT AND PENDING APPLICATIONS				REMITTANT Name, Address			
				EXAMINER Name, Title	DATE 2002		
U. S. PATENT DOCUMENTS							
Ref. No.	Document No.	Serial No.	Kind	Class	Subclass	Foreign Patent Application	
C	AA	5,842,760	Patent	427	257		
C	AB	5,872,428	Patent	427	258-07		
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
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	AO						
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OTHER REFERENCES (including Authors, Title, Date, Document Pages, Etc.)							
C	AF		Bozorth, M. The resistive response as a function of temperature and film thickness of fiber textured Pb-Sr-TiO ₃ thin films grown by				
			PLD using a carbon fiber. Journal of Appl. Phys. 82, 5, 1999, p. 67				
	AM						
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RECEIVED							
				JAN 14 2002			
EXAMINER				DATE CONSIDERED	JAN 14 2002		
TC 1700							

EXAMINER: I would now like to ask you what you think is the difference between MPF 6000 and the other standard methods of calculating the water content of soil?

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
MI22-1657SERIAL NO.
09/905,320LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

FEB 28 2002

APPLICANT: Cem Basceri et al.

FILING DATE
July 13, 2001GROUP
1762

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

EF	AR		DISSERTATION: Cem Basceri, <i>Electrical and Dielectric Properties of (Ba,Sr)TiO₃ Thin Film Capacitors for Ultra-High ...</i> , 171 pages (North Carolina State University, Raleigh 1997).
	AS		
	AT		

EXAMINER

E. Entner

DATE CONSIDERED

5/13/02

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant